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# TEST / CALIBRATION REPORT



**ELECTRONICS REGIONAL TEST LABORATORY (WEST)**  
**MINISTRY OF COMMUNICATIONS & INFORMATION TECHNOLOGY, (STQC Dte.)**

**Government of India**

Plot No. F 7 & 8, MIDC Area, Opp. SEEPZ,  
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## **MEMORANDUM**

The Test/Calibration Report issued by ERTL (W) is a record of the measurements conducted on the products submitted to it for testing / calibration and the results thereof. Unless otherwise specified in the report, the results are applicable only to those products which have been tested / calibrated and do not apply to other products even though declared to be identical.

This Report, if reproduced for any purpose-commercial or otherwise should be reproduced in full, Reproduction of a part of the report or an abstract thereof must be specifically approved from the ERTL (W).

## **LIABILITY CLAUSE**

1. ERTL (W) shall not be liable for any change in test / calibration data and performance specification on account of malfunctioning of the standard / instrument / equipment due to any damage caused to it after the report, in respect of it has been issued.
2. The report shall not be regarded in any way diminishing the normal contractual responsibilities / obligations between the customer and ERTL (W).
3. The results reported in this report are valid only at the time of and under the stated conditions of the measurements.

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DEPARTMENT OF INFORMATION TECHNOLOGY (STQC Dte.)			
SUBJECT: TYPE TESTING OF PANEL METER	DATE	PAGE	OF
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1. SCOPE

1.1 Service Request No : ERTL(W) / 20022611 dated 31-Dec.-2002

1.1.1 Service Request finalised on : 31-Dec.-2002

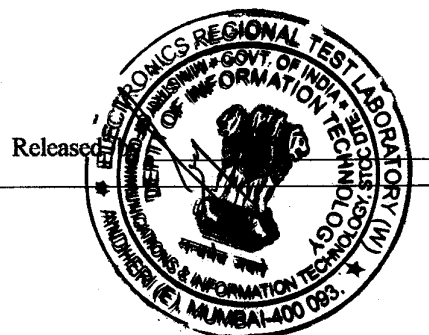
1.2 Requested by : MECO INSTRUMENTS PVT LTD.,  
(Name and address of organisation) 301, BHARAT INDUSTRIAL EASTATE,  
T.J. ROAD, SEWREE (W),  
MUMBAI - 400 015.

1.3 Description	Qty	Manufacturer	Model	Serial Nos.
POWER FACTOR METER, 440 V, 5 A.	03 Nos.	MECO	96QF31	031940 - SAMPLE 1 (S1) 031942 - SAMPLE 2 (S2) 031943 - SAMPLE 3 (S3)

1.4 Test specifications : TYPE TEST AS PER IS 1248 : 1993  
CATEGORY II

1.5 Lab Ambient : Temperature : (25 ±2) deg.C  
Humidity : (55 ±5) % RH

- 1.6 Test Equipment used :
- |                              |           |
|------------------------------|-----------|
| 1. Energy Calibrator         | E&S/126   |
| 2. D.M.M                     | E&S/120   |
| 3. Digital Insulation Tester | E&S/121   |
| 4. W/I Auto Tester           | E&S/066   |
| 5. Environmental Chamber     | ENV/042   |
| 6. Environmental Chamber     | WK 1000-2 |
| 7. Energy Meter Calibrator   | E&S/126   |
| 8. Vibration Machine         | ENV/008   |
| 9. Shock Test Machine        | ENV/018   |

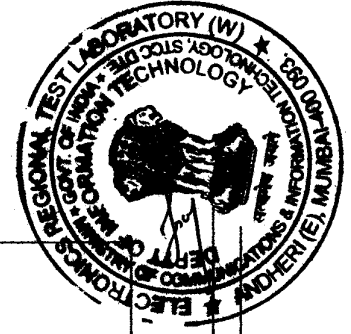


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### 2.0 Test Results

Sr.No.	Test/Parameter	Test Condition	Requirement	Observation			Remark
				S-1	S-2	S-3	
2.1	Insulation Resistance	At 500 V DC for 1 min. between terminals shorted together and body.	Not less than 5 M ohm	> 2000 M ohm	> 2000 M ohm	> 2000 M ohm	Complied
2.2	High Voltage Test	AT 2 kV AC rms for 1 min. between terminals shorted together and foil wrapped on body.	There shall not be any breakdown/ flashover.	No breakdown or flashover observed in case of any of the 3 samples			Complied
2.3	Intrinsic Error	At following equidistant points 1 (0 deg.) 0.9 lead (25.84 deg.) 0.7 lead (45.57 deg.) 0.5 lead (60 deg.) 0.9 lag (-25.84 deg.) 0.7 lag (-45.57 deg.) 0.5 lag (-60 deg.)	Error shall not exceed 3 deg	S - 1 0.35 deg 1.17 deg 0.27 deg 0.7 deg 0.31 deg 0.3 deg 2.05 deg	S - 2 0.65 deg 0.07 deg 0.78 deg 0.8 deg 0.51 deg 0.7 deg 2.37 deg	S - 3 0.75 deg 0.55 deg 0.99 deg 0.9 deg 0.22 deg 0.4 deg 2.05 deg	Complied
2.4	Variation due to influential quantities						
2.4.1	Variation due to ambient temp.	Lower temp. 10 deg. C, Upper temp. 37 deg. C Intrinsic error checked at following equidistant points. 1 (0 deg.) 0.9 lead (25.84 deg.) 0.7 lead (45.57 deg.) 0.5 lead (60 deg.) 0.9 lag (-25.84 deg.) 0.7 lag (-45.57 deg.) 0.5 lag (-60 deg.)	Permissible variation shall be 100% of class index	S - 1 0.14 deg 0.67 deg 0.25 deg 0.01 deg 0.5 deg 0.07 deg 0.7 deg	S - 2 0.11 deg 0.13 deg 0.23 deg 0.08 deg 0.51 deg 0.68 deg 0.74 deg	S - 3 0.13 deg 0.46 deg 0.22 deg 0.29 deg 0.04 deg 0.81 deg 0.32 deg	Complied

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Sr.No.	Test/Parameter	Test Condition	Requirement	Observation	Remark	
2.4.2	Variation due to humidity	Lower Relative humidity 25%, Upper Relative humidity 80% Intrinsic error checked at following equidistant points 1 (0 deg.) 0.9 lead (25.84 deg.) 0.7 lead (45.57 deg.) 0.5 lead (60 deg.) 0.9 lag (-25.84 deg.) 0.7 lag (-45.57 deg.) 0.5 lag (-60 deg.)	Permissible variation shall be 100% of class index	0.14 deg 0.23 deg 1.26 deg 0.2 deg 0.97 deg 0.58 deg 0.66 deg Inductance 0.24 deg Capacitance 0.04 deg	0.77 deg 0.06 deg 0.18 deg 0.20 deg 0.99 deg 0.81 deg 0.60 deg Inductance 0.14 deg Capacitance 0.06 deg	Complied
2.4.3	Variation due to distortion of AC measured quantity	Superimpose 20 % of third harmonics up on the fundamental wave form.	Permissible variation shall be 100% of class index	Inductance 0.14 deg Capacitance 0.04 deg	Inductance 0.06 deg Capacitance 0.04 deg	Complied
2.4.4	Variation due to frequency of AC measured quantity	Frequency varied from 45 Hz to 55 Hz 1 (0 deg.) 0.9 lead (25.84 deg.) 0.7 lead (45.57 deg.) 0.5 lead (60 deg.) 0.9 lag (-25.84 deg.) 0.7 lag (-45.57 deg.) 0.5 lag (-60 deg.)	Permissible variation shall be 100% of class index	0.44 deg 0.78 deg 1.22 deg 1.48 deg 0.52 deg 0.63 deg 0.45 deg	0.27 deg 0.82 deg 1.28 deg 1.44 deg 1.93 deg 0.13 deg 0.53 deg 0.79 deg 0.83 deg 1.44 deg 1.93 deg 0.13 deg 0.53 deg 0.77 deg	Complied

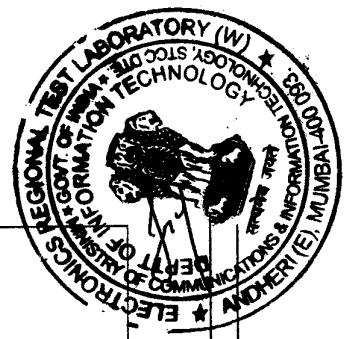
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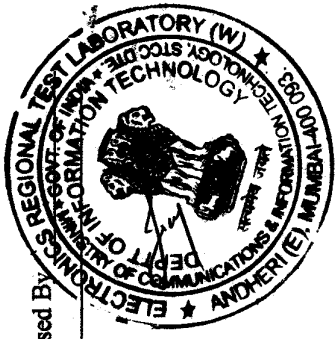
No.	Test/Parameter	Test Condition	Requirement	Observation			Remark
				S-1	S-2	S-3	
4.4	Variation due to position	Intrinsic error to be measured at reference plane and then at 5 deg. Inclination plane in forward, backward, left & right direction. Maximum deviation at following equidistant points 1 (0 deg.) 0.9 lead (25.84 deg.) 0.7 lead (45.57 deg.) 0.5 lead (60 deg.) 0.9 lag (-25.84 deg.) 0.7 lag (-45.57 deg.) 0.5 lag (-60 deg.)	Permissible variation shall be 50% of class index	0.08 deg 0.28 deg 0.06 deg 0.36 deg 0.22 deg 0.44 deg 0.4 deg	0.2 deg 0.35 deg 0.16 deg 0.12 deg 0.4 deg 0.28 deg 0.3 deg	0.16 deg 0.2 deg 0.18 deg 0.13 deg 0.15 deg 0.14 deg 1.16 deg	Complied
2.4.5	Variation due to magnetic field of external origin	AC excitation of upper limit under an external magnetic field of 0.4kA/m. Maximum deviation to be observed.	6 % of fiducial value	Inductance 0.08 deg Capacitance 0.07 deg	Inductance 0.08 deg Capacitance 0.09 deg	Inductance 0.09 deg Capacitance 0.05 deg	Complied
2.4.6	Variation due to ferromagnetic supports	Accuracy test carried out by mounting UUT on Non Ferrous Panel (PVC) & Ferrous Panel at following equidistant points 1 (0 deg.) 0.9 lead (25.84 deg.) 0.7 lead (45.57 deg.) 0.5 lead (60 deg.) 0.9 lag (-25.84 deg.) 0.7 lag (-45.57 deg.) 0.5 lag (-60 deg.)	Within the limit of intrinsic error	0.06 deg 0.1 deg 0.09 deg 0.09 deg 0.15 deg 0.26 deg 0.18 deg	0.17 deg 0.23 deg 0.08 deg 0.14 deg 0.25 deg 0.19 deg 0.22 deg	0.1 deg 0.16 deg 0.28 deg 0.15 deg 0.06 deg 0.25 deg 0.25 deg	Complied

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Sr.No	Test/Parameter	Test Condition	Requirement	Observation			Remark
				S-1	S-2	S-3	
2.4.7	Variation due to conductive supports	Accuracy test carried out by mounting UUT on conductive support at following equidistant points 1 (0 deg.) 0.9 lead (25.84 deg.) 0.7 lead (45.57 deg.) 0.5 lead (60 deg.) 0.9 lag (-25.84 deg.) 0.7 lag (-45.57 deg.) 0.5 lag (-60 deg.)	Shall meet the requirement of intrinsic error	0.17 deg 0.72 deg 0.21 deg 0.19 deg 0.14 deg 0.18 deg 0.2 deg	0.06 deg 0.16 deg 0.16 deg 0.13 deg 0.34 deg 0.76 deg 0.62 deg	0.19 deg 0.02 deg 0.21 deg 0.12 deg 0.1 deg 0.15 deg 0.2 deg	Complied
2.4.9	Variation due to voltage component of measured quantity	Excitation at the middle of the scale. Voltage : 440 V Voltage : 374 V Voltage : 506 V	100 % of class index	0.28 deg	0.39 deg	0.15 deg	Complied
2.6	Self Heating	By applying 90% of upper limit of measuring range for 30 to 35 min. & note down the deviation (%)	Shall comply with the requirements of class index.	Inductance 0.20 deg Capacitance 0.23 deg	Inductance 0.16 deg Capacitance 0.33 deg	Inductance 0.15 deg Capacitance 0.19 deg	Complied



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Sr.No.	Test/Parameter	Test Condition	Requirement	Observation	Remark																					
2.7	Continuous overload	a) By applying 120% of upper limit of voltage for 2h while maintaining current at rated value.  b) Accuracy test at following equidistant points after 2 h. 1 (0 deg.) 0.9 lead (25.84 deg.) 0.7 lead (45.57 deg.) 0.5 lead (60 deg.) 0.9 lag (-25.84 deg.) 0.7 lag (-45.57 deg.) 0.5 lag (-60 deg.)	a) Residual deflection shall not exceed 1% of scale length  b) Shall comply with the accuracy requirement.	No residual deflection observed	Complied																					
				<table border="1" style="width: 100%; border-collapse: collapse;"> <tr> <th style="width: 33%;">S-1</th> <th style="width: 33%;">S-2</th> <th style="width: 33%;">S-3</th> </tr> <tr> <td>0.35 deg</td> <td>0.09 deg</td> <td>0.01 deg</td> </tr> <tr> <td>0.46 deg</td> <td>0.3 deg</td> <td>0.27 deg</td> </tr> <tr> <td>0.43 deg</td> <td>0.09 deg</td> <td>0.03 deg</td> </tr> <tr> <td>0.25 deg</td> <td>0.12 deg</td> <td>0.10 deg</td> </tr> <tr> <td>0.05 deg</td> <td>0.31 deg</td> <td>0.11 deg</td> </tr> <tr> <td>0.32 deg</td> <td>0.13 deg</td> <td>0.12 deg</td> </tr> <tr> <td>0.16 deg</td> <td>0.06 deg</td> <td>0.21 deg</td> </tr> </table>		S-1	S-2	S-3	0.35 deg	0.09 deg	0.01 deg	0.46 deg	0.3 deg	0.27 deg	0.43 deg	0.09 deg	0.03 deg	0.25 deg	0.12 deg	0.10 deg	0.05 deg	0.31 deg	0.11 deg	0.32 deg	0.13 deg	0.12 deg
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		c) By applying 120% of upper limit of current for 2h while maintaining voltage at rated value.  d) Accuracy test at following equidistant points after 2 h. 1 (0 deg.) 0.9 lead (25.84 deg.) 0.7 lead (45.57 deg.) 0.5 lead (60 deg.) 0.9 lag (-25.84 deg.) 0.7 lag (-45.57 deg.) 0.5 lag (-60 deg.)		<table border="1" style="width: 100%; border-collapse: collapse;"> <tr> <td>0.1 deg</td> <td>0.24 deg</td> <td>0.31 deg</td> </tr> <tr> <td>0.86 deg</td> <td>0.17 deg</td> <td>0.24 deg</td> </tr> <tr> <td>0.11 deg</td> <td>0.77 deg</td> <td>0.74 deg</td> </tr> <tr> <td>0.02 deg</td> <td>0.41 deg</td> <td>0.99 deg</td> </tr> <tr> <td>0.26 deg</td> <td>0.06 deg</td> <td>0.11 deg</td> </tr> <tr> <td>0.38 deg</td> <td>0.3 deg</td> <td>0.12 deg</td> </tr> <tr> <td>0.12 deg</td> <td>0.12 deg</td> <td>0.19 deg</td> </tr> </table>	0.1 deg	0.24 deg	0.31 deg	0.86 deg	0.17 deg	0.24 deg	0.11 deg	0.77 deg	0.74 deg	0.02 deg	0.41 deg	0.99 deg	0.26 deg	0.06 deg	0.11 deg	0.38 deg	0.3 deg	0.12 deg	0.12 deg	0.12 deg	0.19 deg	
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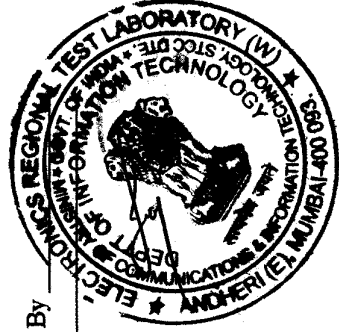
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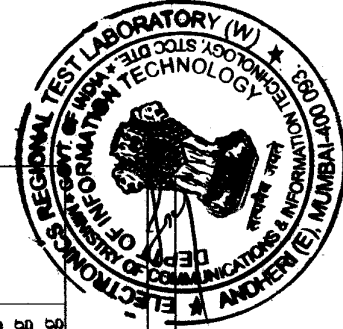
Sr.No.	Test/Parameter	Test Condition	Requirement	Observation	Remark																								
2.8	Overloads of short duration	a) Apply 10 times of the current range while maintaining rated voltage for 0.5s nine times at an interval of 60s and once for 5s. b) Apply 2 times of the voltage range while maintaining rated current for 5s. c) Accuracy test at the following equidistant points : 1 (0 deg.) 0.9 lead (25.84 deg.) 0.7 lead (45.57 deg.) 0.5 lead (60 deg.) 0.9 lag (-25.84 deg.) 0.7 lag (-45.57 deg.) 0.5 lag (-60 deg.)	a) Deviation of index from zero scale mark shall not exceed 1.5% of scale length  b) Shall comply with accuracy requirements.	No deviation observed on any of the three samples.  <table border="1"> <tr> <td>S-1</td> <td>S-2</td> <td>S-3</td> </tr> <tr> <td>0.26 deg</td> <td>0.09 deg</td> <td>0.10 deg</td> </tr> <tr> <td>0.64 deg</td> <td>0.07 deg</td> <td>0.12 deg</td> </tr> <tr> <td>0.05 deg</td> <td>1.15 deg</td> <td>0.61 deg</td> </tr> <tr> <td>0.13 deg</td> <td>0.29 deg</td> <td>1.05 deg</td> </tr> <tr> <td>0.20 deg</td> <td>0.27 deg</td> <td>0.13 deg</td> </tr> <tr> <td>0.32 deg</td> <td>0.2 deg</td> <td>0.04 deg</td> </tr> <tr> <td>0.17 deg</td> <td>0.06 deg</td> <td>0.1 deg</td> </tr> </table>	S-1	S-2	S-3	0.26 deg	0.09 deg	0.10 deg	0.64 deg	0.07 deg	0.12 deg	0.05 deg	1.15 deg	0.61 deg	0.13 deg	0.29 deg	1.05 deg	0.20 deg	0.27 deg	0.13 deg	0.32 deg	0.2 deg	0.04 deg	0.17 deg	0.06 deg	0.1 deg	Completed
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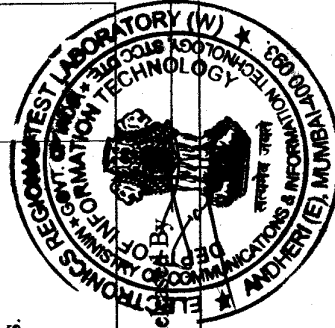
Sr.No.	Test/Parameter	Test Condition	Requirement	Observation	Remark																								
2.9	Environmental Tests																												
2.9.1	Temp. cycling	55 deg.C for 16h & -10 deg.C for 8h. 3 cycles while at 80% of the upper limit of excitation. During the last cycle at the end of 16h and while at high temp. slowly increase & decrease the excitation until index reaches the upper limit of measuring range & return to zero. Similarly after 8h at lower temp. slowly increase & decrease the excitation until index reaches the upper limit of measuring range & return to zero.	To be conditioned	Conditioned. Indices were responding to excitation change.	-----																								
2.9.2	Post Measurement. Intrinsic error	At the following equidistant points : 1 (0 deg.) 0.9 lead (25.84 deg.) 0.7 lead (45.57 deg.) 0.5 lead (60 deg.) 0.9 lag (-25.84 deg.) 0.7 lag (-45.57 deg.) 0.5 lag (-60 deg.)	Error shall be within class index	<table border="1"> <thead> <tr> <th>S-1</th> <th>S-2</th> <th>S-3</th> </tr> </thead> <tbody> <tr> <td>0.45 deg</td> <td>0.37 deg</td> <td>0.62 deg</td> </tr> <tr> <td>0.25 deg</td> <td>0.56 deg</td> <td>0.07 deg</td> </tr> <tr> <td>0.03 deg</td> <td>0.25 deg</td> <td>0.04 deg</td> </tr> <tr> <td>0.30 deg</td> <td>0.21 deg</td> <td>0.09 deg</td> </tr> <tr> <td>0.83 deg</td> <td>1.01 deg</td> <td>0.21 deg</td> </tr> <tr> <td>0.77 deg</td> <td>1.3 deg</td> <td>0.28 deg</td> </tr> <tr> <td>2.09 deg</td> <td>2.81 deg</td> <td>1.86 deg</td> </tr> </tbody> </table>	S-1	S-2	S-3	0.45 deg	0.37 deg	0.62 deg	0.25 deg	0.56 deg	0.07 deg	0.03 deg	0.25 deg	0.04 deg	0.30 deg	0.21 deg	0.09 deg	0.83 deg	1.01 deg	0.21 deg	0.77 deg	1.3 deg	0.28 deg	2.09 deg	2.81 deg	1.86 deg	Complied
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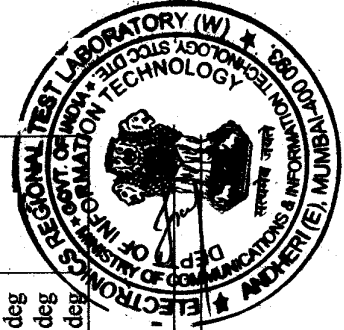
Sr.No.	Test/Parameter	Test Condition	Requirement	Observation	Remark																								
2.9.3	Damp Heat Cyclic Test	As per IS 9000, Part 5 Sec. 1 (16+8) h cycle. 2 cycles. Recovery 24 h.	To be conditioned	Conditioned																									
2.9.4	Post Measurement. Intrinsic error	At the following equidistant points : 1 (0 deg.) 0.9 lead (25.84 deg.) 0.7 lead (45.57 deg.) 0.5 lead (60 deg.) 0.9 lag (-25.84 deg.) 0.7 lag (-45.57 deg.) 0.5 lag (-60 deg.)	Class index	<table border="1"> <tr> <th>S - 1</th> <th>S - 2</th> <th>S - 3</th> </tr> <tr> <td>0.90 deg</td> <td>0.90 deg</td> <td>0.90 deg</td> </tr> <tr> <td>0.88 deg</td> <td>0.02 deg</td> <td>0.68 deg</td> </tr> <tr> <td>0.25 deg</td> <td>0.21 deg</td> <td>0.33 deg</td> </tr> <tr> <td>0.49 deg</td> <td>0.75 deg</td> <td>0.06 deg</td> </tr> <tr> <td>0.64 deg</td> <td>0.86 deg</td> <td>0.46 deg</td> </tr> <tr> <td>0.72 deg</td> <td>1.02 deg</td> <td>0.63 deg</td> </tr> <tr> <td>2.19 deg</td> <td>2.52 deg</td> <td>2.11 deg</td> </tr> </table>	S - 1	S - 2	S - 3	0.90 deg	0.90 deg	0.90 deg	0.88 deg	0.02 deg	0.68 deg	0.25 deg	0.21 deg	0.33 deg	0.49 deg	0.75 deg	0.06 deg	0.64 deg	0.86 deg	0.46 deg	0.72 deg	1.02 deg	0.63 deg	2.19 deg	2.52 deg	2.11 deg	Complied
S - 1	S - 2	S - 3																											
0.90 deg	0.90 deg	0.90 deg																											
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0.72 deg	1.02 deg	0.63 deg																											
2.19 deg	2.52 deg	2.11 deg																											
2.10	Deviation from zero	Energise the samples for 30s at upper limit of measuring range. Quickly reduce the excitation to zero. Deviation from zero shall be measured 15s after the excitation has been reduced to zero.	Deviation expressed as percentage of scale length shall not exceed more than 50% of class index.	No deviation observed in any of the three samples.	Complied																								



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Sr.No.	Test/Parameter	Test Condition	Requirement	Observation																								
2.11	Vibration test	As per IS 9000 Part 8 Sweep range: 10-150-10 Hz Displacement amplitude: 0.15 mm peak in the range 10-60 Hz, Acceleration: 2g in the range: 60-150 Hz, Sweep Rate: 1 octave/min., Duration : 6 h. Endurance shall be performed at resonance frequency. Vibration shall be applied at the resonance frequency for 6h in that direction. If the resonance is observed in any of these 3 directions, the equipment shall be subjected to vibration at each of the frequencies 25, 50, 100 and 150 Hz in each of the 3 mutually perpendicular direction so that the total duration shall not exceed 6 h.	To be conditioned	Conditioned. No visual damage observed																								
2.12	Accuracy Test (Post Vibration)	At the following equidistant points : 1 (0 deg.) 0.9 lead (25.84 deg.) 0.7 lead (45.57 deg.) 0.5 lead (60 deg.) 0.9 lag (-25.84 deg.) 0.7 lag (-45.57 deg.) 0.5 lag (-60 deg.)	Error shall not deviate more than 50% of class index	<table border="1"> <thead> <tr> <th>S-1</th> <th>S-2</th> <th>S-3</th> </tr> </thead> <tbody> <tr> <td>0.36 deg</td> <td>0.47 deg</td> <td>0.22 deg</td> </tr> <tr> <td>0.99 deg</td> <td>0.66 deg</td> <td>0.1 deg</td> </tr> <tr> <td>0.90 deg</td> <td>0.19 deg</td> <td>0.16 deg</td> </tr> <tr> <td>0.75 deg</td> <td>0.51 deg</td> <td>0.51 deg</td> </tr> <tr> <td>0.46 deg</td> <td>0.04 deg</td> <td>0.48 deg</td> </tr> <tr> <td>0.46 deg</td> <td>0.13 deg</td> <td>0.52 deg</td> </tr> <tr> <td>0.03 deg</td> <td>0.09 deg</td> <td>0.18 deg</td> </tr> </tbody> </table>	S-1	S-2	S-3	0.36 deg	0.47 deg	0.22 deg	0.99 deg	0.66 deg	0.1 deg	0.90 deg	0.19 deg	0.16 deg	0.75 deg	0.51 deg	0.51 deg	0.46 deg	0.04 deg	0.48 deg	0.46 deg	0.13 deg	0.52 deg	0.03 deg	0.09 deg	0.18 deg
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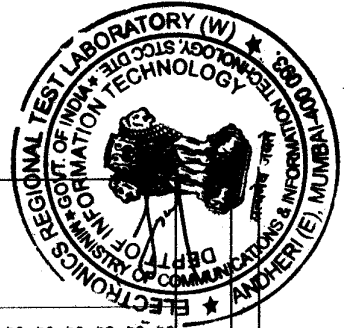
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Sr.No.	Test/Parameter	Test Condition	Requirement	Observation	Remark																								
2.13	Shock Test	As per IS 9000 P-7, Peak Acceleration: 15g. Pulse shape: half sine, Duration: 11 ms, 3 shocks in both directions of 3 mutually perpendicular axes (total 18 shocks)	To be conditioned	Conditioned	----																								
2.14	Accuracy Test (Post Shock)	At the following equidistant points : 1 (0 deg.) 0.9 lead (25.84 deg.) 0.7 lead (45.57 deg.) 0.5 lead (60 deg.) 0.9 lag (-25.84 deg.) 0.7 lag (-45.57 deg.) 0.5 lag (-60 deg.)	Error after test shall not deviate by more than 100% of class index from the original values measured before shock test.	<table border="1"> <tr> <th>S-1</th> <th>S-2</th> <th>S-3</th> </tr> <tr> <td>0.01 deg</td> <td>0.03 deg</td> <td>0.18 deg</td> </tr> <tr> <td>0.09 deg</td> <td>0.17 deg</td> <td>0.03 deg</td> </tr> <tr> <td>0.13 deg</td> <td>0.01 deg</td> <td>0.25 deg</td> </tr> <tr> <td>0.17 deg</td> <td>0.20 deg</td> <td>0.33 deg</td> </tr> <tr> <td>0.01 deg</td> <td>0 deg</td> <td>0.24 deg</td> </tr> <tr> <td>0.06 deg</td> <td>0.16 deg</td> <td>0.15 deg</td> </tr> <tr> <td>0.01 deg</td> <td>0.13 deg</td> <td>0.19 deg</td> </tr> </table>	S-1	S-2	S-3	0.01 deg	0.03 deg	0.18 deg	0.09 deg	0.17 deg	0.03 deg	0.13 deg	0.01 deg	0.25 deg	0.17 deg	0.20 deg	0.33 deg	0.01 deg	0 deg	0.24 deg	0.06 deg	0.16 deg	0.15 deg	0.01 deg	0.13 deg	0.19 deg	Complied
S-1	S-2	S-3																											
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0.01 deg	0.13 deg	0.19 deg																											
2.15	Life Test	The UUT shall be subjected to 1,50,000 full scale deflections, the impulse supplied being of such amplitude that the pointer reaches max. value of the scale without impinging on the end stop. ON for 1 sec OFF for 4 sec during one cycle.	To be conditioned	Conditioned	----																								
2.16	Accuracy Test (Post Life Test)	At the following equidistant points : 1 (0 deg.) 0.9 lead (25.84 deg.) 0.7 lead (45.57 deg.) 0.5 lead (60 deg.) 0.9 lag (-25.84 deg.) 0.7 lag (-45.57 deg.) 0.5 lag (-60 deg.)	Error shall be within class index	<table border="1"> <tr> <th>S-1</th> <th>S-2</th> <th>S-3</th> </tr> <tr> <td>0.8 deg</td> <td>0.48 deg</td> <td>0.30 deg</td> </tr> <tr> <td>1.15 deg</td> <td>0.44 deg</td> <td>0.30 deg</td> </tr> <tr> <td>0.55 deg</td> <td>0.3 deg</td> <td>0.68 deg</td> </tr> <tr> <td>0.39 deg</td> <td>0.85 deg</td> <td>0.86 deg</td> </tr> <tr> <td>0.61 deg</td> <td>0.04 deg</td> <td>0.30 deg</td> </tr> <tr> <td>1.04 deg</td> <td>0.08 deg</td> <td>0.22 deg</td> </tr> <tr> <td>0.29 deg</td> <td>0.18 deg</td> <td>0.06 deg</td> </tr> </table>	S-1	S-2	S-3	0.8 deg	0.48 deg	0.30 deg	1.15 deg	0.44 deg	0.30 deg	0.55 deg	0.3 deg	0.68 deg	0.39 deg	0.85 deg	0.86 deg	0.61 deg	0.04 deg	0.30 deg	1.04 deg	0.08 deg	0.22 deg	0.29 deg	0.18 deg	0.06 deg	Complied
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3.0 **General Remarks** : Nil.

REPORT APPROVED BY

9 REP

*[Signature]*  
HEAD (E&S)



## OUR ACCREDITATION STATUS

ERTL (W) set up under the STQC Directorate, Ministry of Communications & Information Technology, Govt. of India has been accredited under number of national / international systems as follows :

SYSTEM	AREA	STATUS
<p><b>IECQ</b> (International Electro-technical Commission on Quality Assessment System for Electronic Components)</p>	<p><b>Component Testing</b></p> <ul style="list-style-type: none"> <li>• Resistors (Fixed)</li> <li>• Capacitors (Fixed)</li> </ul>	<p><b>Accredited as ITL</b> (Independent Test Laboratory)</p>
<p><b>NABL (C), India</b> National Accreditation Board for Test &amp; Calibration laboratories (Calibration System)</p>	<p><b>Calibration</b></p> <ul style="list-style-type: none"> <li>• Electro-technical discipline</li> <li>• Thermal discipline</li> <li>• Mechanical discipline</li> </ul>	<p>Accredited Calibration Laboratory</p>
<p><b>NABL (T), India</b> National Accreditation Board for Test &amp; Calibration laboratories (Testing System)</p>	<p>Electronic &amp; Electrical Testing</p>	<p>Accredited Test Laboratory</p>
<p><b>IECEE-CB-Scheme</b></p>	<ul style="list-style-type: none"> <li>• Mains Operated Electronic Consumer Products</li> <li>• IT Products</li> <li>• Safety critical</li> <li>• Components</li> </ul>	<p>Approved as a CB Test Laboratory</p>
<p><b>Other recognitions</b></p>		<p>Recognised by CSPO of State Govt., DOT, Naval Docyard. LCSO, RDSO &amp; DRSO</p>